UNIVERSITY OF LIMERICK
OLLSCOIL LUIMNIGH
Bernal Institute

Carryscope

Overview

The JEOL CarryScope delivers high resolution performance imaging of conventional electron microscopes, making it easy to observe high and low magnifications of fine surface structures and digitally record images. Standard features include 8X to 300,000X imaging and up to 5.0nm resolution. The CarryScope produces a sharp image that makes it possible to conduct and annotate high precision measurements on sub-micron structures.

Scanning Electron Microscope JEOL JCM-5700 CarryScope

Contact
Bernal Institute
E: bernal.institute@ul.ie